

1200 V, 75 A Fast Field-Stop IGBT 7 with SiC Diode

APT75GH120JSC30



Product Overview

1200 V, 75 A Fast Field-Stop IGBT with co-packaged anti-parallel SiC diode, SOT-227

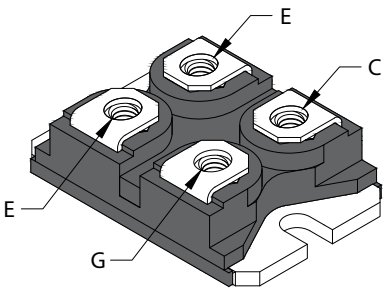
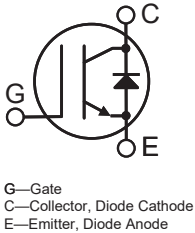


Table 1. Ordering Information

Catalog Part Number (CPN)	Package	Packing Media	Qualification
APT75GH120JSC30	SOT-227	Tube	Industrial

Features

- Low conduction loss and saturation voltage
- Fast switching
- Low gate charge
- Ultrafast tail current shutoff
- No reverse recovery
- Reverse-bias safe operating area (RBSOA) rated
- Easy to parallel
- RoHS compliant
- Zero E_{on} switching loss from co-packaged, anti-parallel diode
- Isolated voltage to 2500 V, UL certified file E145592 

1. Device Specifications

This section shows the specifications of this device.

1.1. Absolute Maximum Ratings

The following table shows the absolute maximum ratings of this device. $T_C = 25\text{ }^{\circ}\text{C}$ unless otherwise specified.

Table 1-1. Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
V_{CES}	Collector-emitter voltage	1200	V
V_{GE}	Gate-emitter voltage	± 20	
I_{C1}	Continuous collector current ¹ ($T_C = 25\text{ }^{\circ}\text{C}$)	118	A
I_{C2}	Continuous collector current ¹ ($T_C = 100\text{ }^{\circ}\text{C}$)	72	
I_{CM}	Pulsed collector current ² ($T_C = 175\text{ }^{\circ}\text{C}$)	225	
RBSOA	Reverse-bias safe operating area ($T_J = 150\text{ }^{\circ}\text{C}$, 960 V)	225	A
P_D	Total power dissipation	375	W

Notes:

- Limited by maximum lead temperature.
- Repetitive rating: Pulse width and case temperature are limited by the maximum junction temperature.

1.2. Thermal and Mechanical Characteristics

The following table shows the thermal and mechanical characteristics of this device.

Table 1-2. Thermal and Mechanical Characteristics

Symbol	Characteristic	Min.	Typ.	Max.	Unit
$R_{\theta JC}$	Junction-to-case thermal resistance (IGBT)		0.28	0.40	$^{\circ}\text{C}/\text{W}$
$R_{\theta JC}$	Junction-to-case thermal resistance (diode)		0.60	0.87	
T_J, T_{STG}	Operating and storage junction temperature	-40		175	$^{\circ}\text{C}$
$V_{ISOLATION}$	RMS voltage (50 Hz–60 Hz sinusoidal waveform from terminals to mounting base for 1 minute)	2500			V
τ_M	Mounting torque, M3 screw for heat sink attachment (requires 2, not included)		0.8		N·m
τ_T	Terminal screw torque, M4 screw (4 included)			1.1	
Wt	Package weight		29.2		g

1.3. Electrical Performance

The following table shows the static characteristics of this device. $T_C = 25\text{ }^{\circ}\text{C}$ unless otherwise specified.

Table 1-3. Static Characteristics

Symbol	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
$V_{GE(th)}$	Gate threshold voltage	$V_{CE} = V_{GE}, I_C = 1.2\text{ mA}$	4.7	5.5	6.2	V
$V_{CE(on)}$	Collector-emitter on voltage	$V_{GE} = 15\text{ V}, I_C = 75\text{ A}$		1.7	2.15	
		$V_{GE} = 15\text{ V}, I_C = 75\text{ A}, T_J = 175\text{ }^{\circ}\text{C}$		2.0		
I_{CES}	Collector cut-off current ¹	$V_{CE} = 1200\text{ V}, V_{GE} = 0\text{ V}$			240	μA
		$V_{CE} = 1200\text{ V}, V_{GE} = 0\text{ V}, T_J = 175\text{ }^{\circ}\text{C}$		4750		

Table 1-3. Static Characteristics (continued)

Symbol	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
I_{GES}	Gate-emitter leakage current	$V_{GE} = \pm 20\text{ V}$			± 100	nA

Note:

1. I_{CES} includes both IGBT and diode leakages.

The following table shows the dynamic characteristics of this device. $T_C = 25\text{ }^\circ\text{C}$ unless otherwise specified.

Table 1-4. Dynamic Characteristics

Symbol	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
C_{ies}	Input capacitance	$V_{GE} = 0\text{ V}, V_{CE} = 25\text{ V}, f = 1\text{ MHz}$		9835		pF
C_{res}	Reverse transfer capacitance			50		
C_{oes}	Output capacitance			128		
V_{GEP}	Gate-to-emitter plateau voltage	$V_{GE} = 15\text{ V}, V_{CE} = 960\text{ V}, I_C = 75\text{ A}$		7.5		V
Q_G	Total gate charge ¹			538		nC
Q_{GE}	Gate-emitter charge			66		
Q_{GC}	Gate-collector ("Miller") charge			198		
RBSOA	Reverse-bias safe operating area	$T_J = 175\text{ }^\circ\text{C}, R_G = 23\text{ }\Omega, V_{GE} = 15\text{ V}, V_{CE} = 800\text{ V}, L = 100\text{ }\mu\text{H}$	300			A
$t_{d(on)}$	Turn-on delay time	$V_{CC} = 800\text{ V}, V_{GE} = 15\text{ V}, I_C = 75\text{ A}, R_G = 5\text{ }\Omega, T_J = 25\text{ }^\circ\text{C}$		32		ns
t_r	Current rise time			53		
$t_{d(off)}$	Turn-off delay time			311		
t_f	Current fall time			32		
E_{on}	Turn-on switching energy ²	$V_{CC} = 800\text{ V}, V_{GE} = 15\text{ V}, I_C = 75\text{ A}, R_G = 5\text{ }\Omega, T_J = 125\text{ }^\circ\text{C}$		4222		μJ
E_{off}	Turn-off switching energy ³			2584		
$t_{d(on)}$	Turn-on delay time			32		ns
t_r	Current rise time			53		
$t_{d(off)}$	Turn-off delay time	$V_{CC} = 800\text{ V}, V_{GE} = 15\text{ V}, I_C = 75\text{ A}, R_G = 5\text{ }\Omega, T_J = 125\text{ }^\circ\text{C}$		354		
t_f	Current fall time			45		
E_{on}	Turn-on switching energy ²			4556		μJ
E_{off}	Turn-off switching energy ³			3693		

Notes:

1. See MIL-STD-750 Method 3471.
2. E_{on} is the clamped inductive turn-on-energy of this device; there is no contribution to E_{on} from the SiC diode. (See [Figure 1-19](#), [Figure 1-20](#).)
3. E_{off} is the clamped inductive turn-off energy measured in accordance with JEDEC standard JESD24-1. (See [Figure 1-19](#), [Figure 1-21](#).)

1.4. Typical Performance Curves

Data for performance curves are characterized, not 100% tested.

Figure 1-1. Output Characteristics

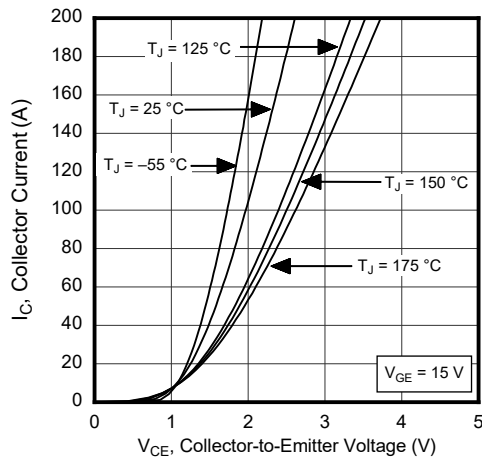


Figure 1-2. Transfer Characteristics

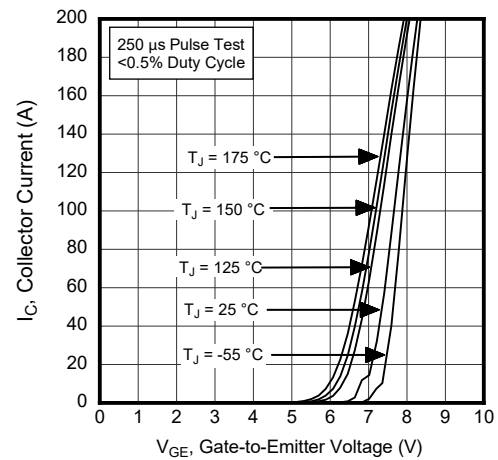


Figure 1-3. Gate Charge

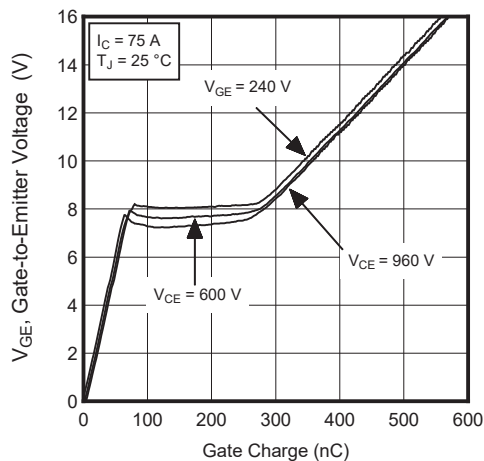


Figure 1-4. On-State Voltage vs. Gate-to-Emitter Voltage

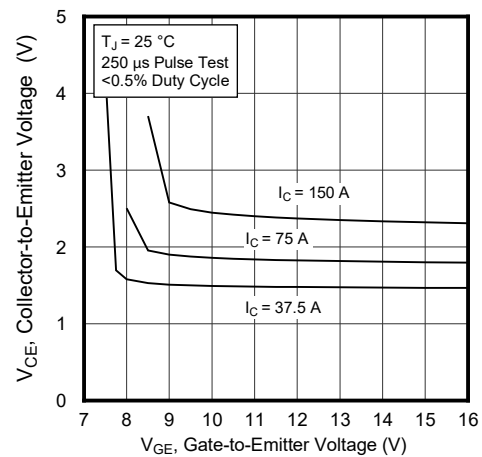


Figure 1-5. On-State Voltage vs. Junction Temperature

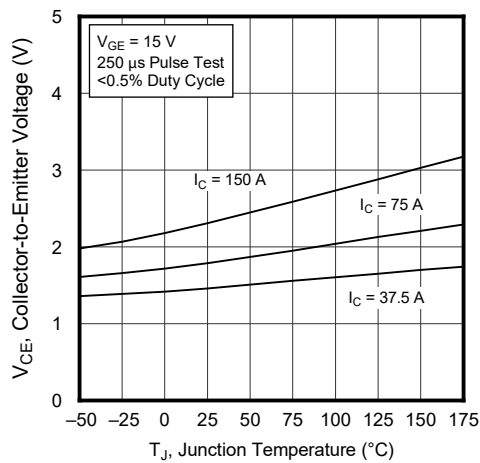


Figure 1-6. DC Collector Current vs. Case Temperature

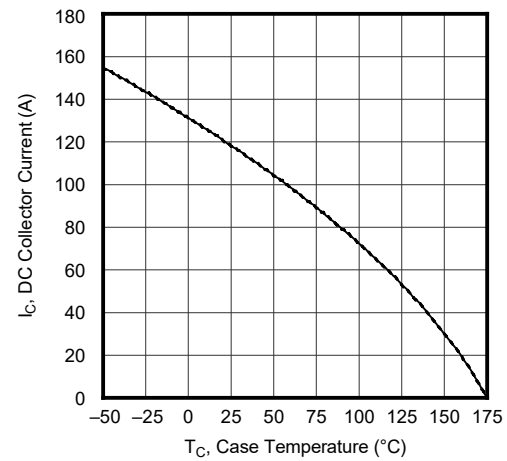


Figure 1-7. Turn-On Delay Time vs. Collector Current

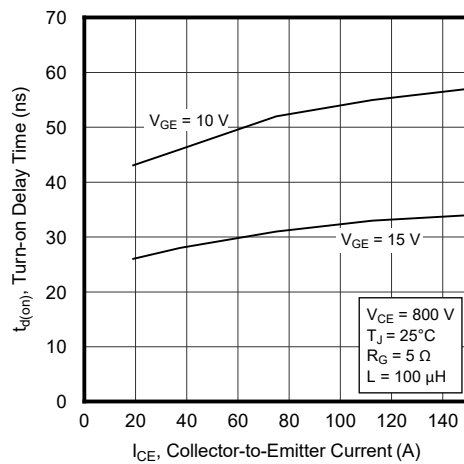


Figure 1-8. Turn-Off Delay Time vs. Collector Current

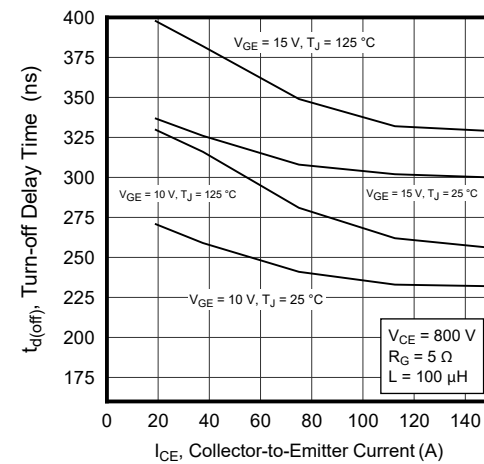


Figure 1-9. Current Rise Time vs. Collector Current

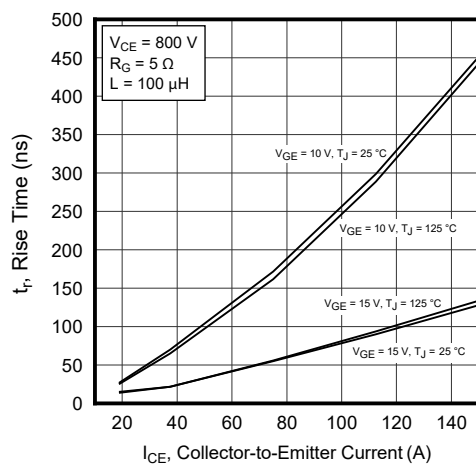


Figure 1-10. Current Fall Time vs. Collector Current

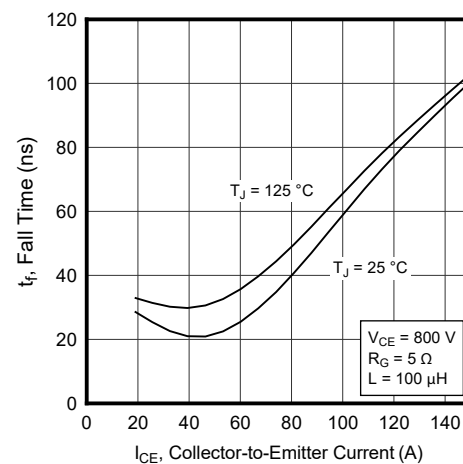


Figure 1-11. Turn-On Energy Loss vs. Collector Current

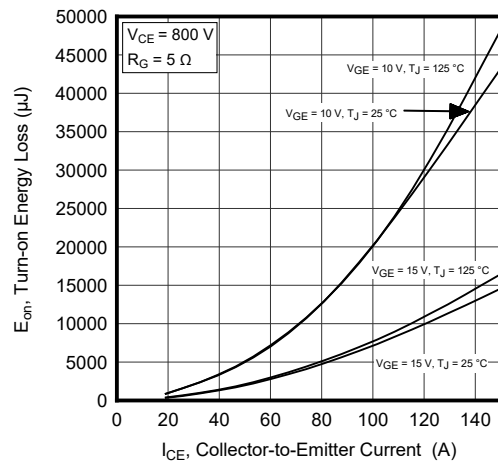


Figure 1-12. Turn-Off Energy Loss vs. Collector Current

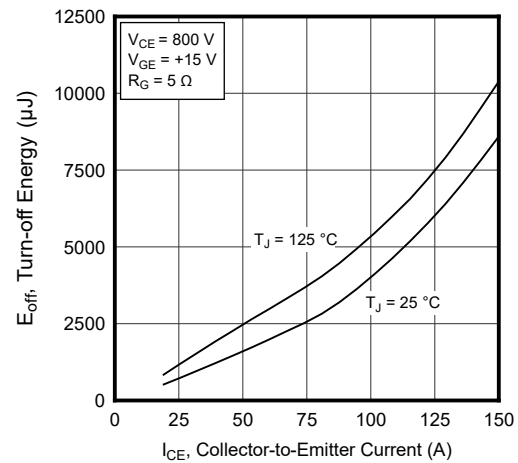


Figure 1-13. Switching Energy Losses vs. Gate Resistance

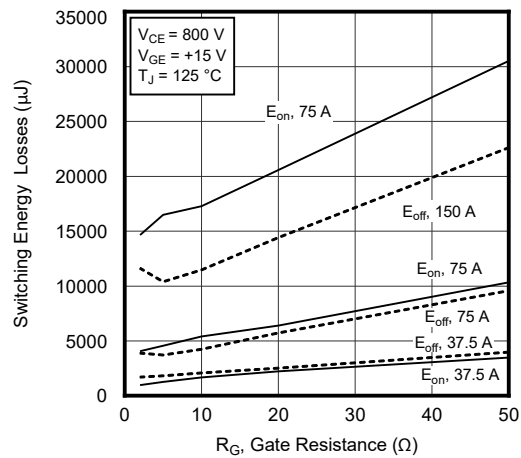


Figure 1-14. Switching Energy Losses vs. Junction Temperature

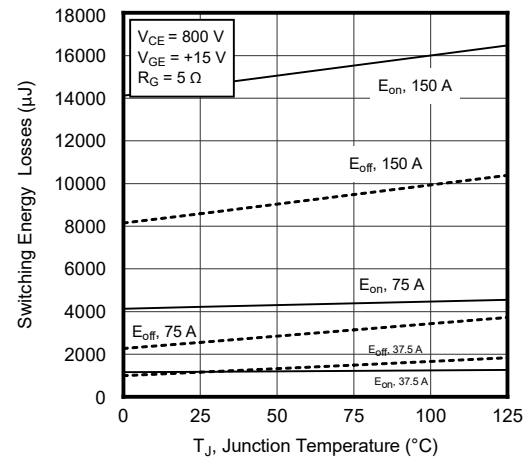


Figure 1-15. Capacitance vs. Collector-To-Emitter Voltage

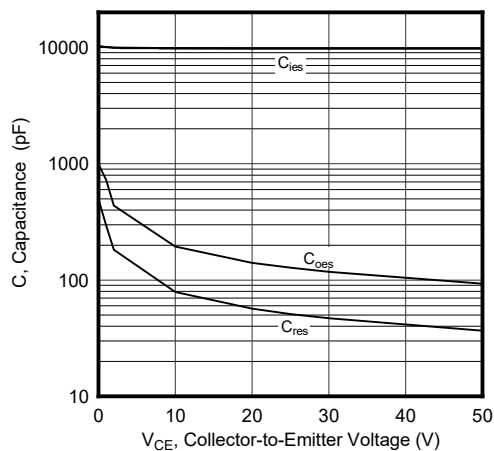


Figure 1-16. Reverse-bias Safe Operating Area

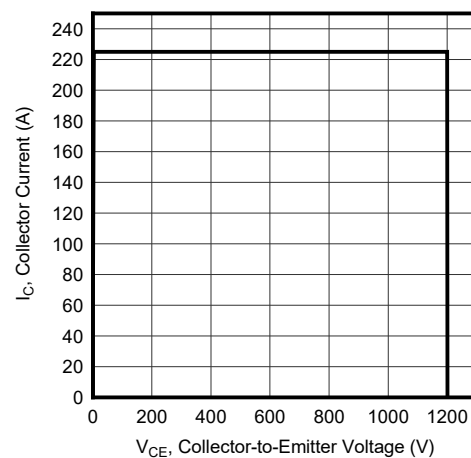


Figure 1-17. Maximum Transient Thermal Impedance

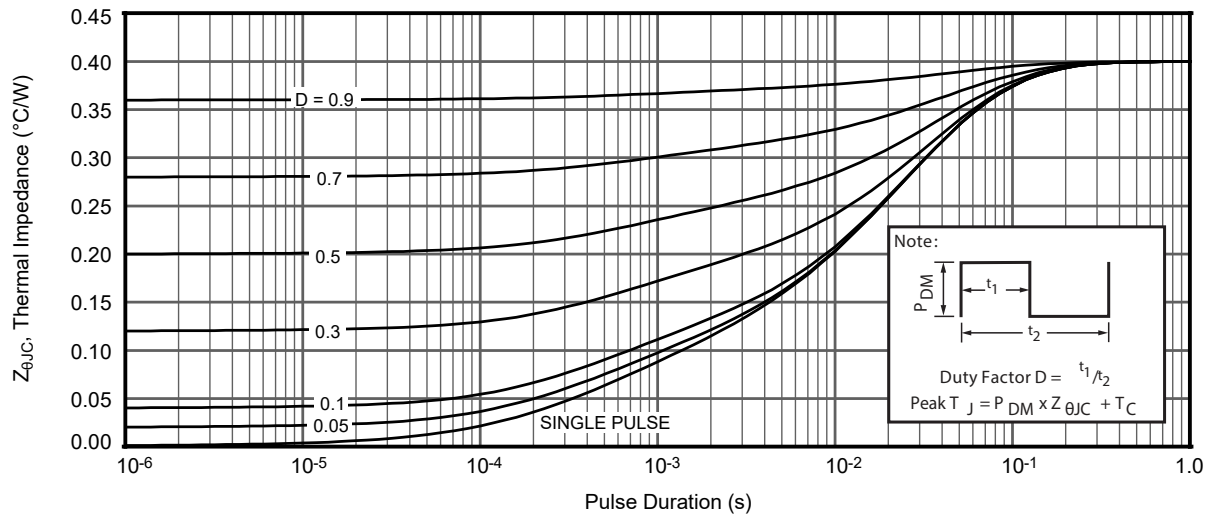


Figure 1-18. Transient Thermal Impedance Model

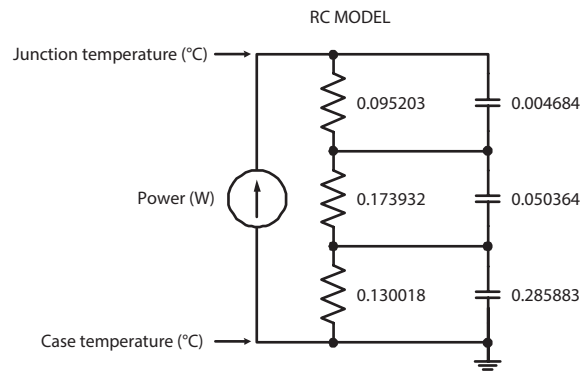


Figure 1-19. Inductive Switching Test Circuit

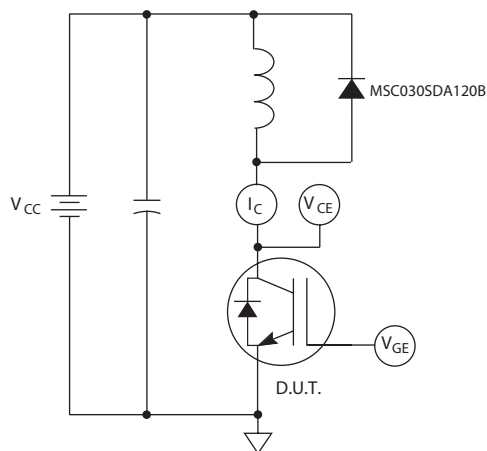


Figure 1-20. Turn-on Switching Waveform and Definitions

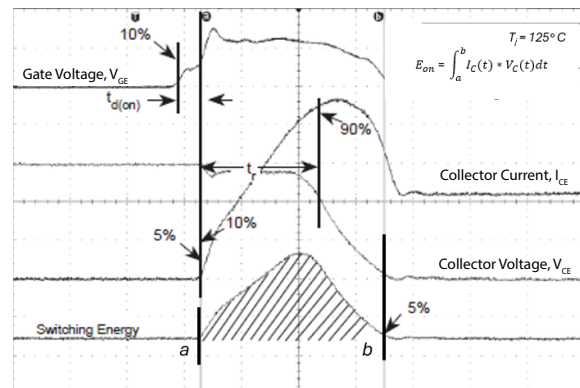
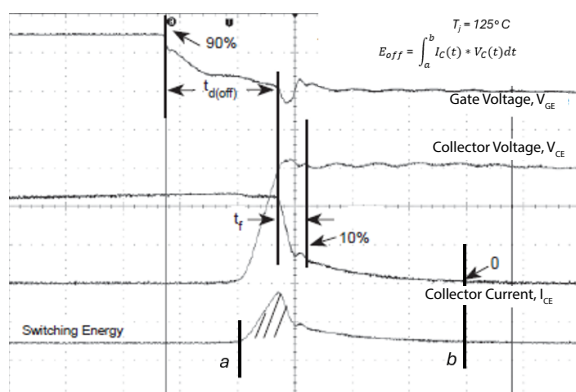


Figure 1-21. Turn-off Switching Waveform and Definitions



2. Device Specifications: Zero-Recovery SiC Anti-Parallel Diode

This section shows the specifications of the co-packaged, anti-parallel diode.

2.1. Absolute Maximum Ratings

The following table shows the absolute maximum ratings of the anti-parallel diode. $T_C = 25\text{ }^{\circ}\text{C}$ unless otherwise specified.

Table 2-1. Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
I_F	Maximum DC forward current ($T_C = 25\text{ }^{\circ}\text{C}$)	65	A
	Maximum DC forward current ($T_C = 135\text{ }^{\circ}\text{C}$)	29	
	Maximum DC forward current ($T_C = 145\text{ }^{\circ}\text{C}$)	24	
I_{FRM}	Repetitive peak forward surge current ($t_p = 8.3\text{ ms}$, half sine wave)	92	W
I_{FSM}	Non-repetitive forward surge current ($t_p = 8.3\text{ ms}$, half sine wave)	165	
P_{TOT}	Total power dissipation ($T_C = 25\text{ }^{\circ}\text{C}$)	259	
	Total power dissipation ($T_C = 110\text{ }^{\circ}\text{C}$)	112	

2.2. Electrical Performance

The following table shows the static characteristics of the anti-parallel diode.

Table 2-2. Static Characteristics

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
V_F	Forward voltage	$I_F = 30\text{ A}$, $T_J = 25\text{ }^{\circ}\text{C}$		1.5	1.8	V
		$I_F = 30\text{ A}$, $T_J = 175\text{ }^{\circ}\text{C}$		2.1		

2.3. Typical Performance Curves

Data for performance curves are characterized, not 100% tested.

Figure 2-1. Maximum Transient Thermal Impedance

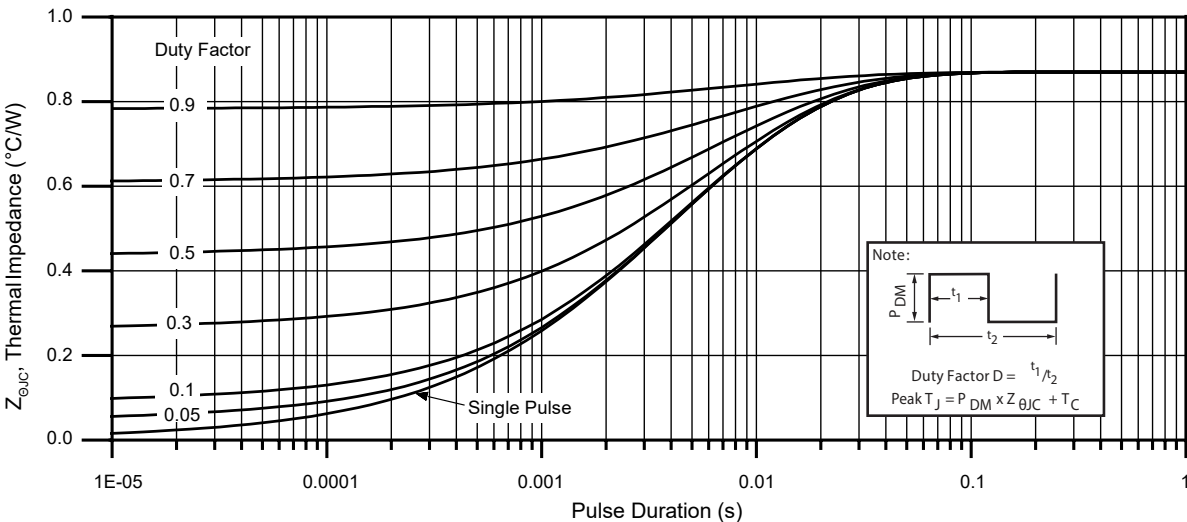
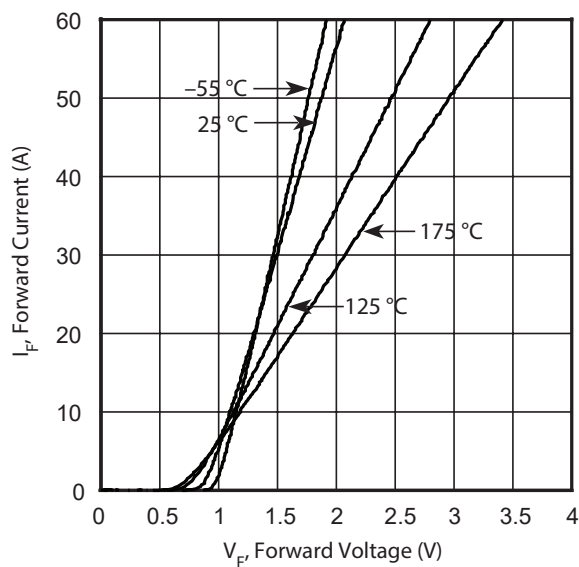
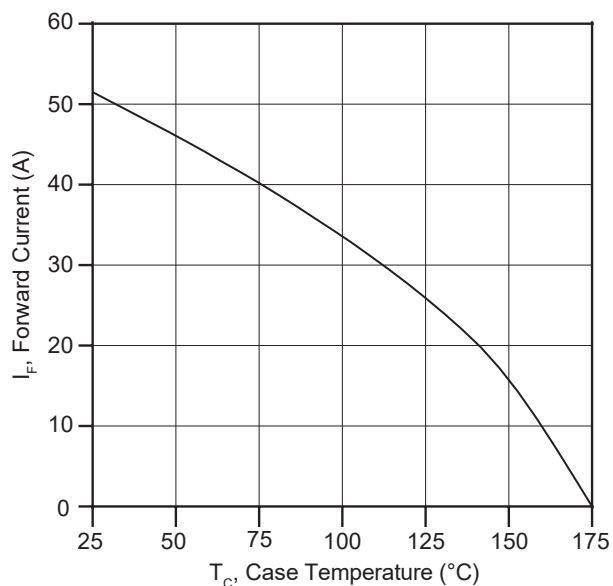
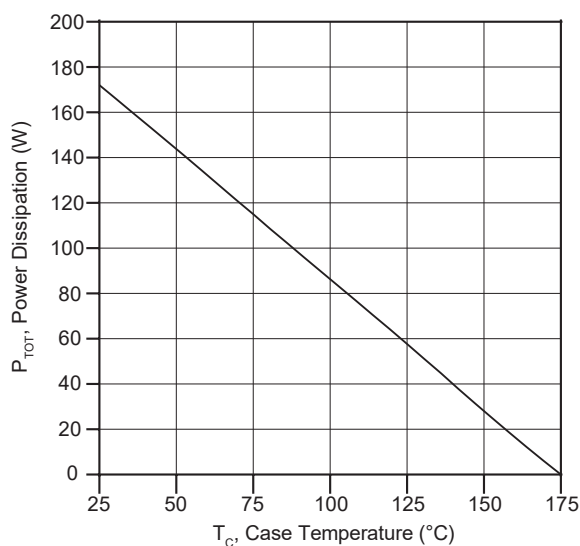
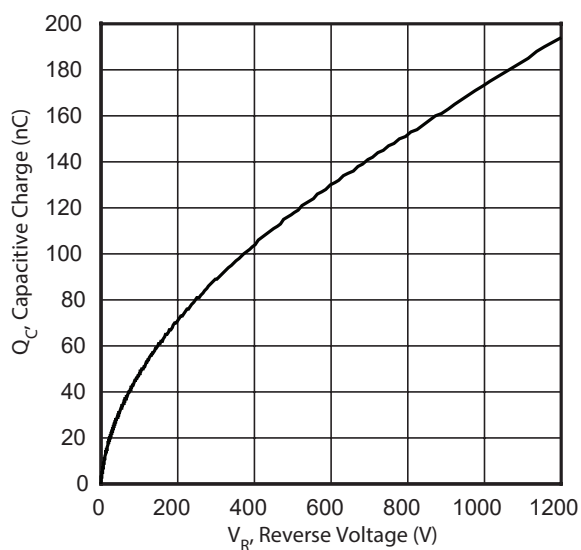


Figure 2-2. Forward Current vs. Forward Voltage**Figure 2-3. Max. Forward Current vs. Case Temp.****Figure 2-4. Max. Power Dissipation vs. Case Temp.****Figure 2-5. Total Capacitive Charge vs. Reverse Voltage**

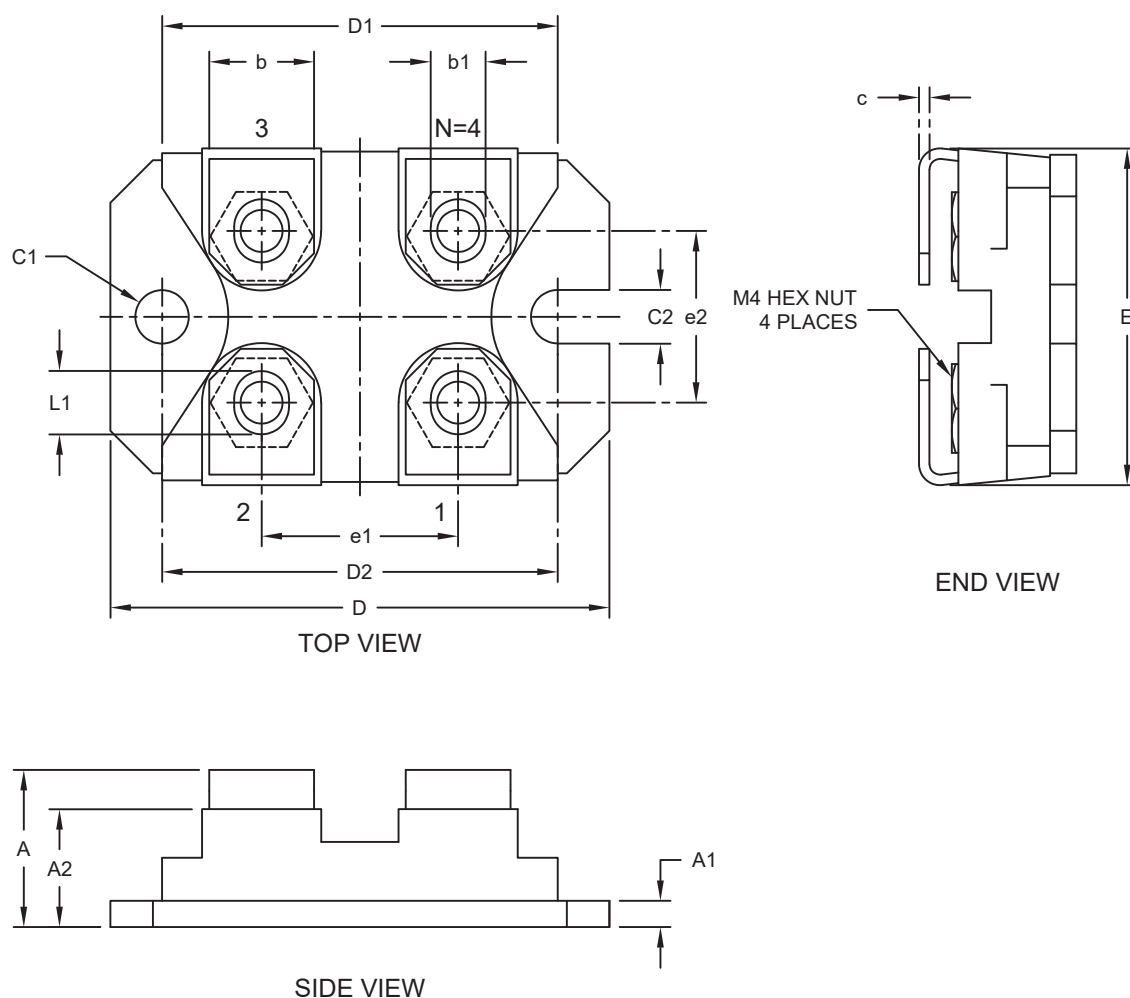
3. Package Specification

This section shows the package specification of this device.

3.1. Package Outline Drawing

The following figure illustrates the SOT-227 package outline of this device.

Figure 3-1. Package Outline Drawing



The following table shows the SOT-227 dimensions and should be used in conjunction with the package outline drawing.

Table 3-1. SOT-227 Dimensions

Dimension Limits		Dimensions (millimeters)	
		Min.	Max.
Number of terminals	N		4
Terminal pitch	e1	14.9	15.1
Terminal pitch	e2	12.6	12.8
Overall height	A	11.8	12.2
Base plate thickness	A1	1.95	2.14

Table 3-1. SOT-227 Dimensions (continued)

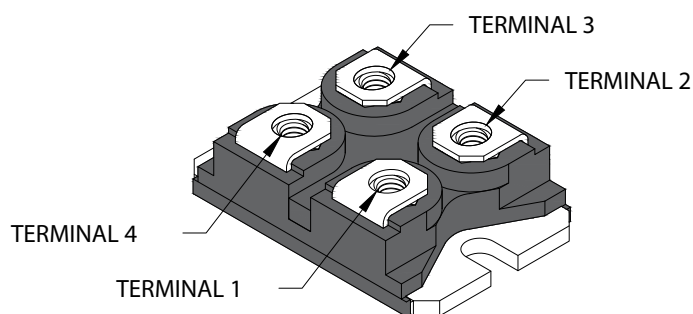
Dimension Limits		Dimensions (millimeters)	
		Min.	Max.
Molded package thickness	A2	8.9	9.6
Overall length	D	38.0	38.2
Molded package length	D1	31.5	31.7
Mounting centers	D2	30.1	30.3
Overall width	E	25.2	25.4
Terminal width	b	7.8	8.2
Terminal thickness	c	0.75	0.85
Terminal slot width	b1	4.1	4.3
Terminal slot length	L1	4.8	4.9
Mounting hole diameter	C1	4.0	4.2
Mounting slot width	C2	4.0	4.2

Note:

1. Dimensioning and tolerancing per ASME Y14.5M.

3.2. Terminal Pinout

The following figure illustrates the terminal pinout of this device.

Figure 3-2. Terminal Pinout

The following table shows the electrical signal terminal pinout of this device.

Table 3-2. Electrical Signal Terminal Pinout

Terminal	Definition
TERMINAL 1	Gate
TERMINAL 2	Collector, Diode Cathode
TERMINAL 3	Emitter, Diode Anode
TERMINAL 4	Emitter, Diode Anode

4. Revision History

The revision history describes the changes that were implemented in the document. The changes are listed by revision, starting with the most current publication.

Table 4-1. Revision History

Revision	Date	Description
A	10/2025	Document created.

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